## Lili Ding

## List of Publications by Year in descending order

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2258059 2053705 5 7 42 3 citations h-index g-index papers 7 7 7 36 docs citations times ranked citing authors all docs

#	Article	IF	CITATIONS
1	Analysis of Ion-Induced SEFI and SEL Phenomena in 90 nm NOR Flash Memory. IEEE Transactions on Nuclear Science, 2021, 68, 2508-2515.	2.0	1
2	The impact of driving capacity on single-event effect vulnerability of standard cell., 2021,,.		0
3	Mutual interference induced by single event effects in CMOS circuits. AIP Advances, 2020, 10, 065020.	1.3	O
4	Modeling the Dependence of Single-Event Transients on Strike Location for Circuit-Level Simulation. IEEE Transactions on Nuclear Science, 2019, 66, 866-874.	2.0	19
5	Analysis of multiple cell upset sensitivity in bulk CMOS SRAM after neutron irradiation. Chinese Physics B, 2018, 27, 038501.	1.4	3
6	Single-Event Multiple Transients in Conventional and Guard-Ring Hardened Inverter Chains Under Pulsed Laser and Heavy-Ion Irradiation. IEEE Transactions on Nuclear Science, 2017, 64, 2511-2518.	2.0	13
7	Analysis of the TID Induced Failure Modes in NOR and NAND Flash Memories. IEEE Transactions on Nuclear Science, 2013, 60, 224-229.	2.0	6